Se	earch Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/749,437	CHANG ET AL.	
Examiner	Art Unit	
Brian S. Kwon	1614	

	SEARCHED			
Class	Subclass	Date	Examiner	
Updated	see search notes	8/14/2007	вк	
		··		

INI	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
514	255.04	8/14/2007	вк	
	266.04			
	253.01			
	<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Updated (STN, EAST, NPL)	8/14/2007	вк	
Updated (Continuity Data, Inventor Name Search)			
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